

FQD1N80-VB Datasheet

N-Channel 800V (D-S) Super Junction Power MOSFET



RoHS
COMPLIANT
HALOGEN
FREE

PRODUCT SUMMARY

| | | |
|---|-----------------|------|
| V_{DS} (V) at T_J max. | 800 | |
| $R_{DS(on)}$ typ. (Ω) at 25 °C | $V_{GS} = 10$ V | 2.38 |
| Q_g max. (nC) | 90 | |
| Q_{gs} (nC) | 11 | |
| Q_{gd} (nC) | 19 | |
| Configuration | Single | |

FEATURES

- Low figure-of-merit (FOM) $R_{on} \times Q_g$
- Low input capacitance (C_{iss})
- Reduced switching and conduction losses
- Ultra low gate charge (Q_g)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial
 - Welding
 - Induction heating
 - Motor drives
 - Battery chargers
 - Renewable energy
 - Solar (PV inverters)

DPAK
(TO-252)



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_C = 25$ °C, unless otherwise noted)

| PARAMETER | | | SYMBOL | LIMIT | UNIT |
|--|-------------------------------------|-------------------------------------|----------------|-------------|-----------------------|
| Drain-source voltage | | | V_{DS} | 800 | V |
| Gate-source voltage | | | V_{GS} | ± 30 | |
| Continuous drain current ($T_J = 150\text{ }^{\circ}\text{C}$) | V_{GS} at 10 V | $T_C = 25\text{ }^{\circ}\text{C}$ | I_D | 2.8 | A |
| | | $T_C = 100\text{ }^{\circ}\text{C}$ | | 1.8 | |
| Pulsed drain current ^a | | | I_{DM} | 5 | |
| Linear derating factor | | | | 0.5 | W/ $^{\circ}\text{C}$ |
| Single pulse avalanche energy ^b | | | E_{AS} | 14 | mJ |
| Maximum power dissipation | | | P_D | 62.5 | W |
| Operating junction and storage temperature range | | | T_J, T_{stg} | -55 to +150 | $^{\circ}\text{C}$ |
| Drain-source voltage slope | $T_J = 125\text{ }^{\circ}\text{C}$ | | dV/dt | 70 | V/ns |
| Reverse diode dV/dt ^d | | 0.13 | | | |
| Soldering recommendations (peak temperature) ^c | For 10 s | | | 300 | $^{\circ}\text{C}$ |


Notes

- Repetitive rating; pulse width limited by maximum junction temperature
- $V_{DD} = 140$ V, starting $T_J = 25$ °C, $L = 28.2$ mH, $R_g = 25$ Ω , $I_{AS} = 0.9$ A
- 1.6 mm from case
- $I_{SD} \leq I_D$, $dI/dt = 100$ A/ μ s, starting $T_J = 25$ °C

THERMAL RESISTANCE RATINGS

| PARAMETER | SYMBOL | TYP. | MAX. | UNIT |
|----------------------------------|------------|------|------|------|
| Maximum junction-to-ambient | R_{thJA} | - | 62 | °C/W |
| Maximum junction-to-case (drain) | R_{thJC} | - | 2.0 | |

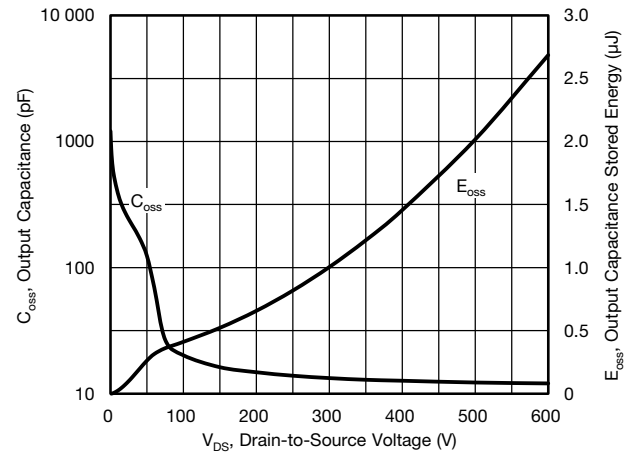
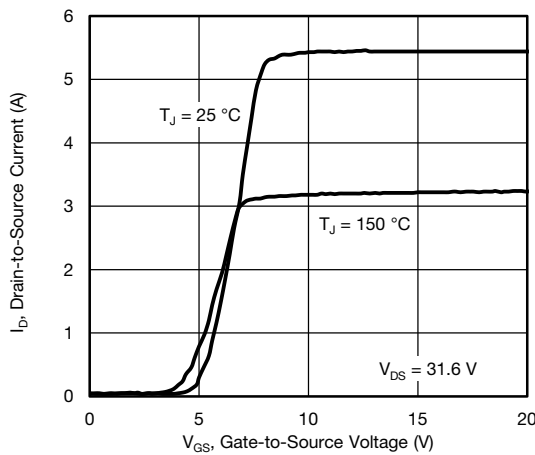
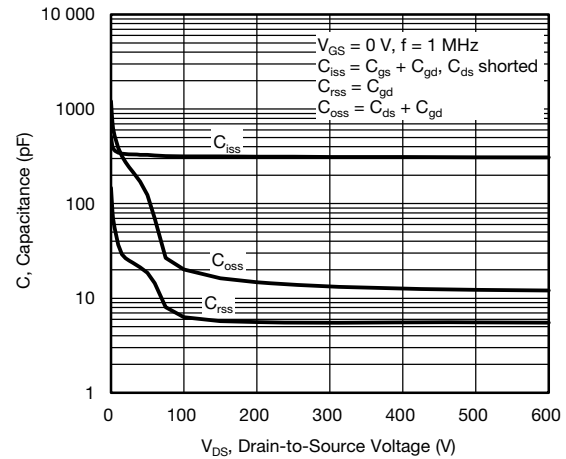
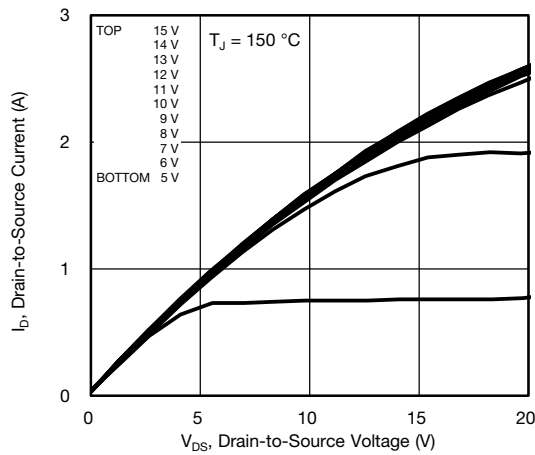
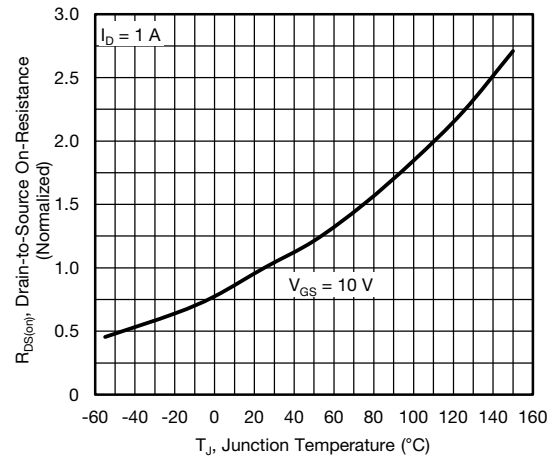
SPECIFICATIONS ($T_J = 25\text{ }^{\circ}\text{C}$, unless otherwise noted)

| PARAMETER | SYMBOL | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
|---|----------------------------------|--|---|------|------|-------|------|
| Static | | | | | | | |
| Drain-source breakdown voltage | V _{DS} | V _{GS} = 0 V, I _D = 250 μA | | 800 | - | - | V |
| V _{DS} temperature coefficient | ΔV _{DS} /T _J | Reference to 25 °C, I _D = 1 mA | | - | 1.0 | - | V/°C |
| Gate-source threshold Voltage (N) | V _{GS(th)} | V _{DS} = V _{GS} , I _D = 250 μA | | 2.0 | - | 4.0 | V |
| Gate-source leakage | I _{GSS} | V _{GS} = ± 20 V | | - | - | ± 100 | nA |
| | | V _{GS} = ± 30 V | | - | - | ± 1 | μA |
| Zero gate voltage drain current | I _{DSS} | V _{DS} = 800 V, V _{GS} = 0 V | | - | - | 1 | μA |
| | | V _{DS} = 640 V, V _{GS} = 0 V, T _J = 125 °C | | - | - | 10 | |
| Drain-source on-state resistance | R _{DS(on)} | V _{GS} = 10 V | I _D = 1.0 A | - | 2.38 | - | Ω |
| Forward transconductance | g _{fs} | V _{DS} = 30 V, I _D = 1.0 A | | - | 1.0 | - | S |
| Dynamic | | | | | | | |
| Input capacitance | C _{iss} | V _{GS} = 0 V, V _{DS} = 100 V, f = 1 MHz | | - | 315 | - | pF |
| Output capacitance | C _{Oss} | | | - | 20 | - | |
| Reverse transfer capacitance | C _{rss} | | | - | 6 | - | |
| Effective output capacitance, energy related ^a | C _{O(er)} | V _{DS} = 0 V to 480 V, V _{GS} = 0 V | | - | 13 | - | |
| Effective output capacitance, time related ^b | C _{O(tr)} | | | - | 45 | - | |
| Total gate charge | Q _g | V _{GS} = 10 V | I _D = 1.0 A, V _{DS} = 480 V | - | 9.8 | 19.6 | nC |
| Gate-source charge | Q _{gs} | | | - | 2.4 | - | |
| Gate-drain charge | Q _{gd} | | | - | 3.9 | - | |
| Turn-on delay time | t _{d(on)} | V _{DD} = 480 V, I _D = 1.0 A, V _{GS} = 10 V, R _g = 9.1 Ω | | - | 11 | 22 | ns |
| Rise time | t _r | | | - | 7 | 14 | |
| Turn-off delay time | t _{d(off)} | | | - | 19 | 38 | |
| Fall time | t _f | | | - | 27 | 54 | |
| Gate input resistance | R _g | f = 1 MHz, open drain | | 1.8 | 3.6 | 7.2 | Ω |
| Drain-Source Body Diode Characteristics | | | | | | | |
| Continuous source-drain diode current | I _S | MOSFET symbol showing the integral reverse p - n junction diode  | | - | - | 2.8 | A |
| Pulsed diode forward current | I _{SM} | | | - | - | 5 | |
| Diode forward voltage | V _{SD} | T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V | | - | - | 1.2 | V |
| Reverse recovery time | t _{rr} | T _J = 25 °C, I _F = I _S = 1.0 A, dI/dt = 100 A/μs, V _R = 25 V | | - | 278 | 556 | ns |
| Reverse recovery charge | Q _{rr} | | | - | 0.9 | 1.8 | μC |
| Reverse recovery current | I _{RRM} | | | - | 5 | - | A |

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS}
 b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS}

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



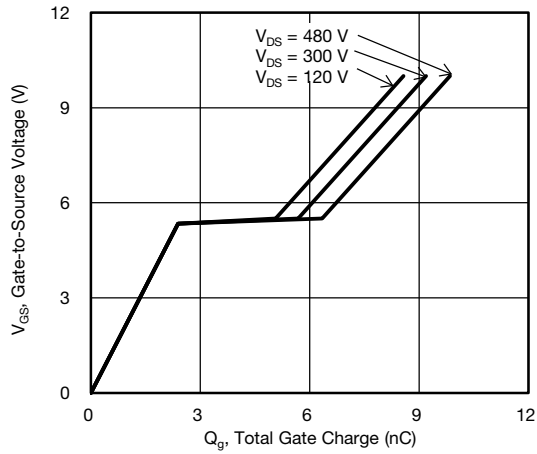


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

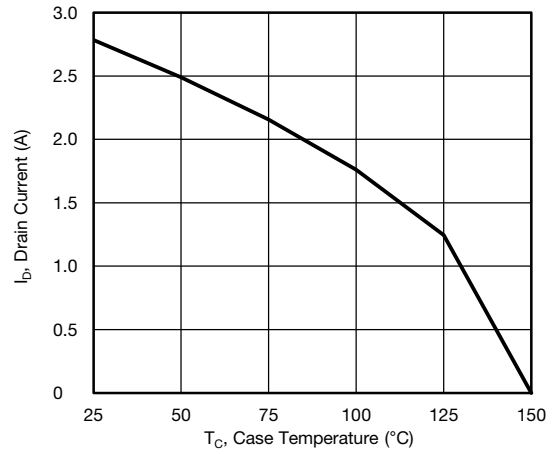


Fig. 10 - Maximum Drain Current vs. Case Temperature

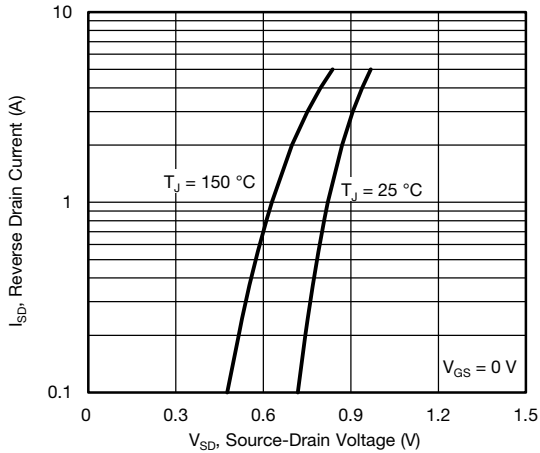


Fig. 8 - Typical Source-Drain Diode Forward Voltage

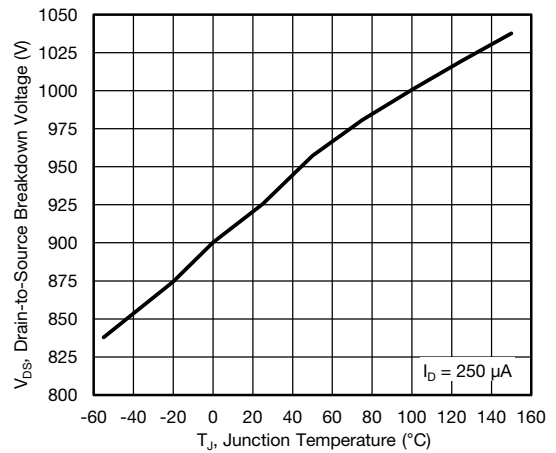


Fig. 11 - Temperature vs. Drain-to-Source Voltage



Fig. 9 - Maximum Safe Operating Area

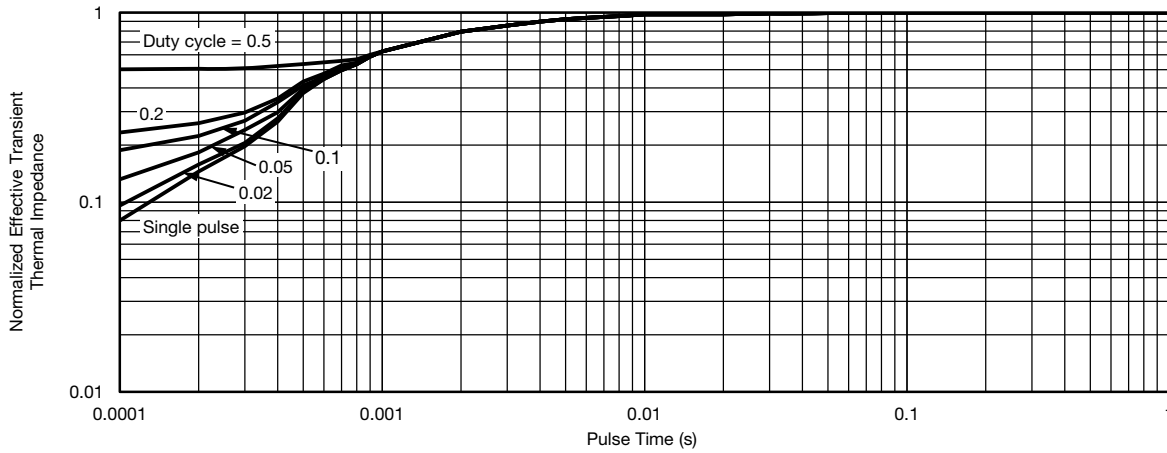


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

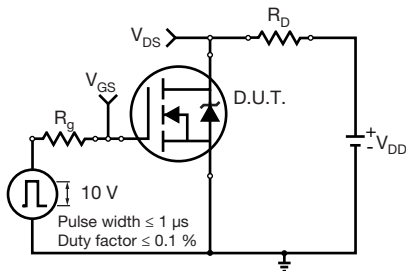


Fig. 13 - Switching Time Test Circuit

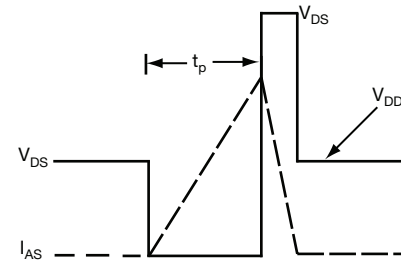


Fig. 16 - Unclamped Inductive Waveforms

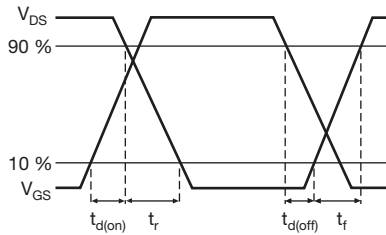


Fig. 14 - Switching Time Waveforms

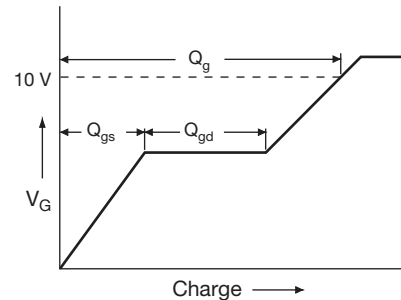


Fig. 17 - Basic Gate Charge Waveform

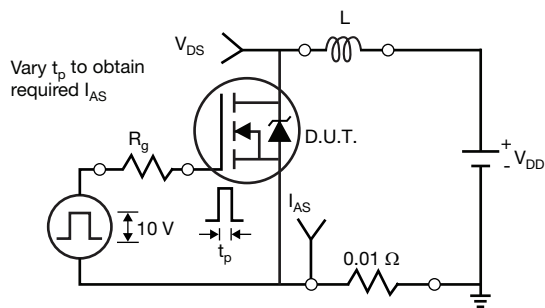


Fig. 15 - Unclamped Inductive Test Circuit

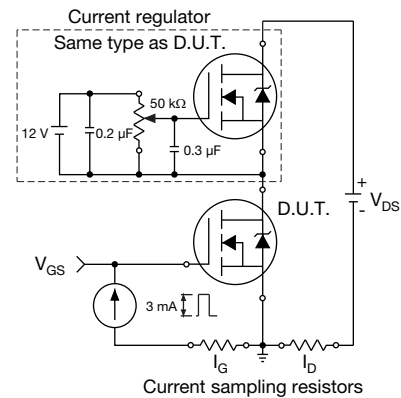


Fig. 18 - Gate Charge Test Circuit



Fig. 19 - For N-Channel

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